

Application No.: 10/709,723

Docket No.: 22171-00016-US1

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions and listings of claims in the application:

LISTING OF CLAIMS:

Please do not  
enter in the  
file.

THANKS!  
Emily Chan

8/8/05

1. (Previously presented) A probe device for electrically testing an integrated circuit device, the probe device comprising:
  - an insulative body including at least one opening;
  - at least one supporter positioned inside the at least one opening of the insulative body, wherein the supporter comprises a helical spring with a spiral coil extending substantially in a same plane;
  - a probe positioned substantially at a center of the supporter, wherein the probe is arranged to electrically connect to a pad of the integrated circuit device during testing; and
  - a conductive wire positioned in the insulative body and electrically connected to the supporter.
2. (Currently amended) The probe device of Claim 1, further comprising two supporters positioned substantially in parallel with each other inside the at least one opening of the insulative body.
3. (Canceled).
4. (Canceled)
5. (Canceled).
6. (Canceled).
7. (Canceled).